Performance of insertion devices on third-generation synchrotron x-ray sources*

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A wide spectrum of advanced insertion devices (ID) developed in recent years provides synchrotron radiation users with new experimental capabilities. Record high brilliance, variable polarization and ahigh degree of the spatial coherence delivered by these IDs stimulated the success of scientific programs at third-generation synchrotron radiation sources.

In order to achieve a state-of-the-art performance level, the ID's design, fabrication and test process should utilize the most advanced "tools" and techniques. If these techniques are properly applied, the synchrotron radiation user should expect the ID radiation output to be practically the same as theoretically predicted.

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